CT/FCT TEST PROBES

Spring-loaded test probe GKS-075 214 064 A 2000 LH

Item GKS-075-0770





- Well-established test probes for contacting PCBs
- For optimal contact to the test points (e.g. pads, vias, and pins), various tip styles with various diameters and finishes are available.
- Various spring forces available as well as versions with stainless steel springs suitable for high temperatures
- Used for setting the optimum stroke conditions in the test fixture, various installation heights can be achieved by combining test probes and receptacles

General data

Product group ICT / FCT (in-circuit test and function test Standard stroke test probe Sub-product group GKS-075 LH long version Series 1.91 mm [75 mil] Grid Contacting from Pad, Pin, Post Magnetic Yes Installation type Plug-in Quick-exchange system Yes Adjustable installation height No Non-rotating No Compatible receptacle(s) KS-075 Min. temperature - 40 °C [- 104 °F] + 80 °C [+ 176 °F] Max. temperature RoHS-compliant RoHS-3;6a



Current load capacity / rated current 3 A
Typical resistance (Ri) <20 mOhm

Mechanical data

 Total length
 35.1 mm [1.38 in]

 Barrel diameter
 1.02 mm [.040 in]

 Maximum stroke
 6.35 mm [.25 in]

 Spring pre-load
 0.85 N [3.05 ozf]

 Collar height
 00

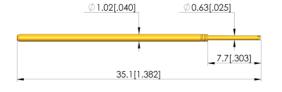
 Spring force at working stroke
 2 N [7.19 ozf]

 Recommended working stroke
 4.3 mm [.169 in]

Tip style data

Tip style 14 4-point crown, self-cleaning
Tip diameter 0.64 mm [.025 in]
Tip style surface A gold
Tip style material 2 steel



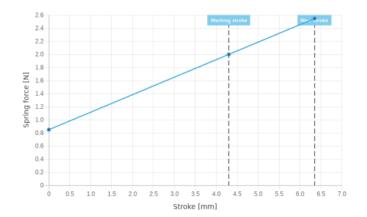




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Learn more about ICT/FCT Test probes

